

CLAIMS

1. A device for the determination of at least one characteristic of electromagnetic radiation from an object under test that includes a support intended to receive the said objet and a network of probes distributed in a more or less circular arc, characterised in that it includes means that allow the relative tilting of the network of probes, and of the support, in the plane of the network of probes or parallel to the latter, in order to angularly shift the network of probes and the support with respect to each other and thus allow measurements to be taken at several relative angular positions of the network of probes and of the object under test.

2. A device according to claim 1, characterised in that the means which allow the relative pivoting of the network of probes and of the support include means capable of tilting the support in relation to the ground.

3. A device according to one of the preceding claims, characterised in that the means that allow the relative tilting of the network of probes and of the support include means that are able to tilt the network of probes in relation to the ground.

4. A device according to one of the preceding claims, characterised in that the relative tilting means of the network of probes and of the support are able to allow a relative angular shifting of the network of probes and of the support that is less than the angular pitch of the network of probes.

5. A device according to claim 4, characterised in that the relative tilting means of the network of probes and of the support are able to allow a relative angular shifting of the

network of probes and of the support corresponding to a fraction of the angular pitch of the network of probes.

6. A device according to one of the preceding claims, characterised in that the relative tilting means of the network of probes and of the support are able to allow a relative angular shifting of the network of probes and of the support at least equal to the angular pitch of the network of probes.

7. A device according to one of the preceding claims, characterised in that it is of the type that includes means that are able to drive the support and the arc in relative rotation around a principal axis of rotation that is more or less merged with a diameter of the latter.

8. A device according to one of the preceding claims, characterised in that it is of the type that includes means that are able to displace the object under test relatively to the network of probes and perpendicularly to the plane of the latter.

9. A method for the determination of at least one characteristic of electromagnetic radiation from an object under test by means of a device that includes a support intended to receive the said objet, and a network of probes distributed over a more or less circular arc, in which the said objet is positioned on the said support, and the network of probes is then used to execute a series of measurements corresponding to different positions of the object under test in relation to the said network of probes, characterised in that the device is a device according to one of the preceding claims, and in that the network of probes and the support are tilted in relation to each other in the plane of the network of probes or parallel to the latter, in order to perform acquisitions at several angular positions of the network of probes in relation to the object under test.

10. A method according to claim 9, characterised in that the device is a device according to claim 7, in that the arc and/or the support are driven in rotation around their main axis in order to place them in several relative positions, and in that for each of these positions of rotation, the network of probes and the support are tilted in relation to each other in the plane of the network of probes or parallel to the latter, in order to perform acquisitions at several angular positions of the network of probes in relation to the object under test.

11. A method according to claim 9, characterised in that the device is a device according to claim 8, in that the arc or the support are moved perpendicularly to the plane of the arc in order to place them in several relative positions, and in that for each of these positions, the network of probes and the support are tilted in relation to each other in the plane of the network of probes or parallel to the latter, in order to perform acquisitions at several angular positions of the network of probes in relation to the object under test.